

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant	:	Li, et al.
App. No.	:	Unknown
Filed	:	Herewith
For	:	ELIMINATION OF DENDRITE FORMATION DURING METAL/CHALCOGENIDE GLASS DEPOSITION
Examiner	:	Unknown
Group Art Unit	:	Unknown

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Enclosed are copies of forms PTO-1449 and 892 listing 29 references. These references are of record in related application No. 10/164,429, filed June 6, 2002. Therefore, copies of the references are not enclosed. This Information Disclosure Statement is being filed upon filing, and no fee is required in accordance with 37 C.F.R. § 1.97(b)(1).

Identification herein is not an admission that any of the foregoing references are prior art to the above-captioned application.

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: June 24, 2003

By: Michael Okamoto

Michael S. Okamoto
Registration No. 47,831
Attorney of Record
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(310) 551-3450

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. MICRON 2501 250C1	APPLICATION NO. 10,104,846 Unknown
	APPLICANT Li, et al.	
	FILING DATE June 6, 2002 June 24, 2003	GROUP 2010 Unknown

COPY

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
		6,348,365	02/19/02	Moore, et al.			
		6,418,049	07/09/02	Kozicki, et al.			

FOREIGN PATENT DOCUMENTS									
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
							YES	NO	

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)						

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EXAMINER	DATE CONSIDERED
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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. MICRON 250A 250C1	APPLICATION NO. 10/404,846 Unknown
	APPLICANT Li, et al.	
	FILING DATE June 6, 2002 June 24, 2003	GROUP 257E Unknown

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	6,487,106	11/26/02	Kozicki			
	2002/0168820	11/14/02	Kozicki, et al.			
	2002/0190350	12/19/02	Kozicki, et al.			
	2003/0035314	02/20/03	Kozicki			
	2003/0035315	02/20/03	Kozicki			
	2003/0048519	03/13/03	Kozicki			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	

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Notice of References Cited	Application/Control No. 10/164,646 Unknown	Applicant(s)/Patent Under Reexamination LI ET AL	
	Examiner DUNGALE Unknown	Art Unit 2818 Unknown	Page 1 of 1

U.S. PATENT DOCUMENTS

* <input checked="" type="checkbox"/>		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
<input checked="" type="checkbox"/>	A	US-2002/0123248	<input checked="" type="checkbox"/> 03-2001	Moore et al.	438/795
<input checked="" type="checkbox"/>	B	US-4,115,872	<input checked="" type="checkbox"/> 09-1978	Bluhm, Vernon A.	257/2
<input type="checkbox"/>	C	US-			
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FOREIGN PATENT DOCUMENTS

* <input type="checkbox"/>		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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<input type="checkbox"/>	R					
<input type="checkbox"/>	S					
<input type="checkbox"/>	T					

NON-PATENT DOCUMENTS

* <input type="checkbox"/>		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
<input type="checkbox"/>	U	
<input type="checkbox"/>	V	
<input type="checkbox"/>	W	
<input type="checkbox"/>	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. MICRON 266A 2504	APPLICATION NO. 10401000 Unknown
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Li, et al.	
		FILING DATE June 6, 2002 June 24, 2003	GROUP Unknown

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	5,761,115	6/2/1998	Kozicki, et al.			
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	5,914,893	6/22/1999	Kozicki, et al.			
	6,084,796	07/04/00	Kozicki, et al.			
	10/164,429	06/06/02	Li, et al.			

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	WO 00/48196	08/17/00	WO				
	WO 02/21542 A1	03/14/02	WO				

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
	P. Boolchand, et al., "Mobile Silver Ions and Glass Formation in Solid Electrolytes" <u>Nature</u> , Vol. 410, April 2001, pp. 1070-1073
	Y. Hirose, et al., "High Speed Memory Behavior and Reliability of an Amorphous As ₂ S ₃ Film Doped With Ag" <u>Physica Status Solidi</u> Vol. (a), No. 16, (1980) K187-K190
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	M. Mitkova, et al., "Dual Chemical Role of Ag as an Additive in Chalcogenide Glasses" <u>Physical Review Letters</u> Vol. 83, No. 19, pp. 3748-3851
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	K. L. Tai, et al., "Inorganic Resist Systems for VLSI Microlithography" pp. 9-35
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